

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
		Examiner Evelyn A. Lester	Art Unit 2873	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,021,003	02-2000	Katsuki et al.	359/619
*	B	US-6,859,229	02-2005	Suda, Yasuo	348/273
*	C	US-5,829,856	11-1998	Perlo et al.	353/84
*	D	US-5,936,773	08-1999	Togino, Takayoshi	359/630
*	E	US-5,973,846	10-1999	McConica, Charles H.	359/642
*	F	US-6,016,222	01-2000	Setani et al.	359/571
*	G	US-6,137,535	10-2000	Meyers, Mark Marshall	348/340
*	H	US-6,373,603	04-2002	Popovich et al.	359/15
*	I	US-2002/0008920	01-2002	Mihara et al.	359/684
*	J	US-2002/0089596	07-2002	Suda, Yasuo	348/302
*	K	US-2002/0149717	10-2002	Borrelli et al.	349/95
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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